



# DYNAMIC FEM ANALYSIS OF MULTIPLE CMUT CELLS IN IMMERSION

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# Outline

- Motivation
- FEM model of an infinite CMUT
- Dynamic FEM analysis
- FEM and experimental results
- Conclusion

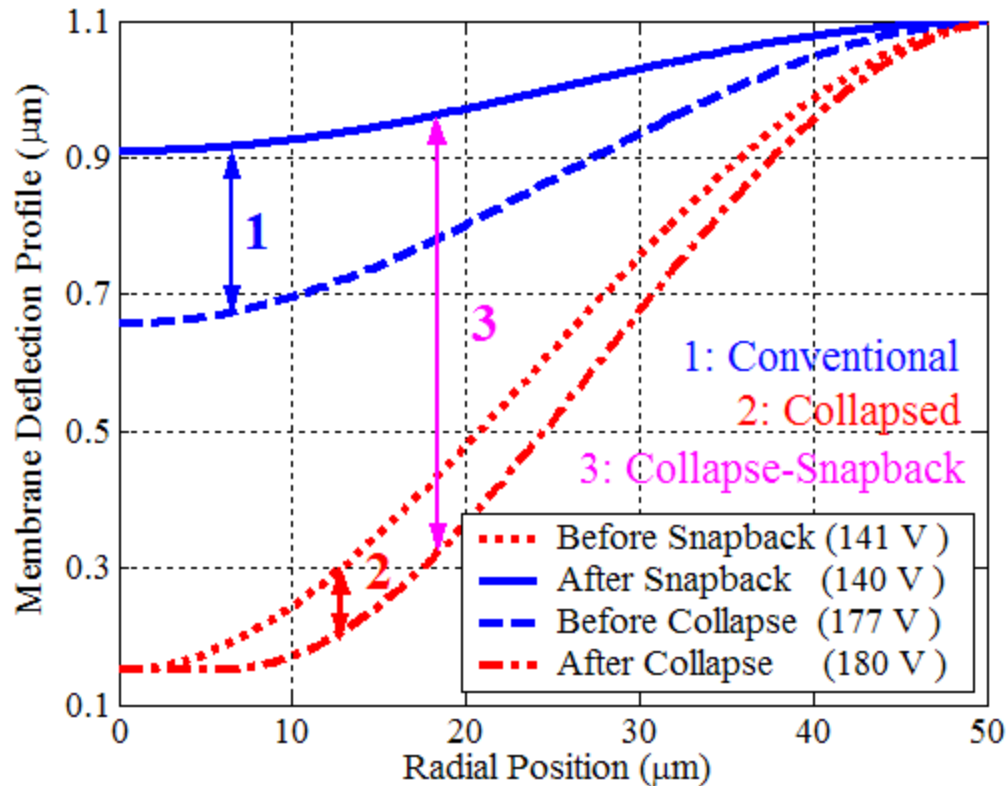


# Motivation

- Goal: To accurately model the cMUT dynamics in “linear” and nonlinear operation regimes using time-domain, finite element method (FEM)
- Test: Operate in different regimes:
  - Conventional (no contact)
  - Collapsed (always in contact)
  - Collapse-snapback (intermittent contact)



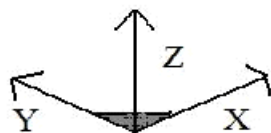
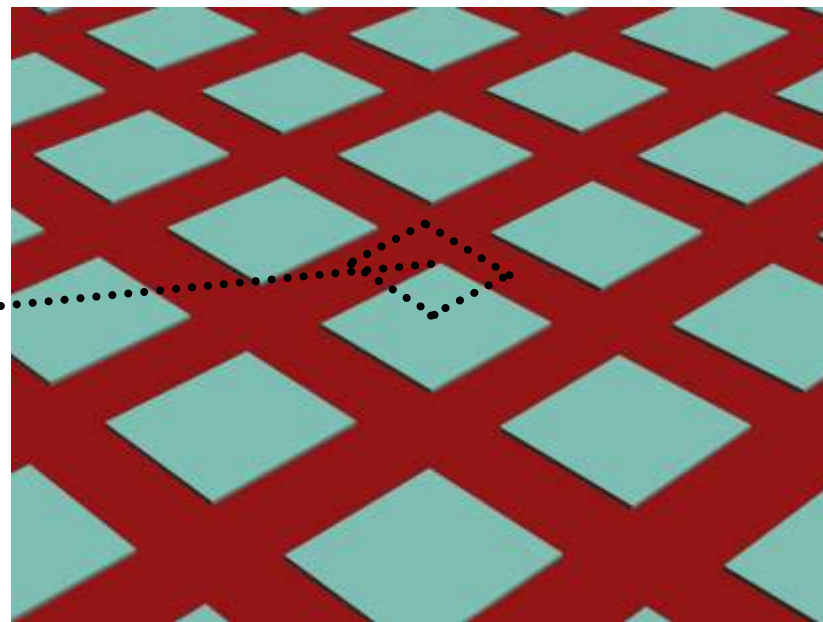
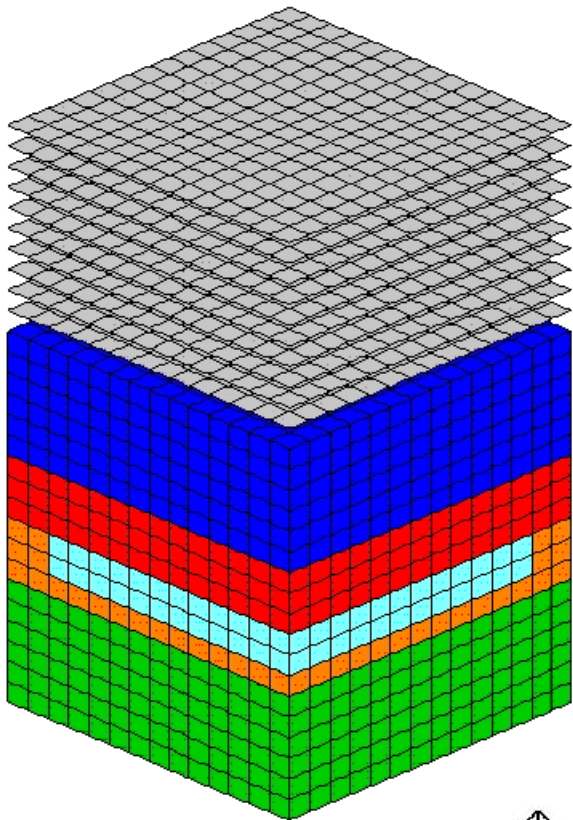
# Different Operation Regimes



Conventional, Collapsed and Collapse-Snapback Operations



# FEM model of an infinite CMUT



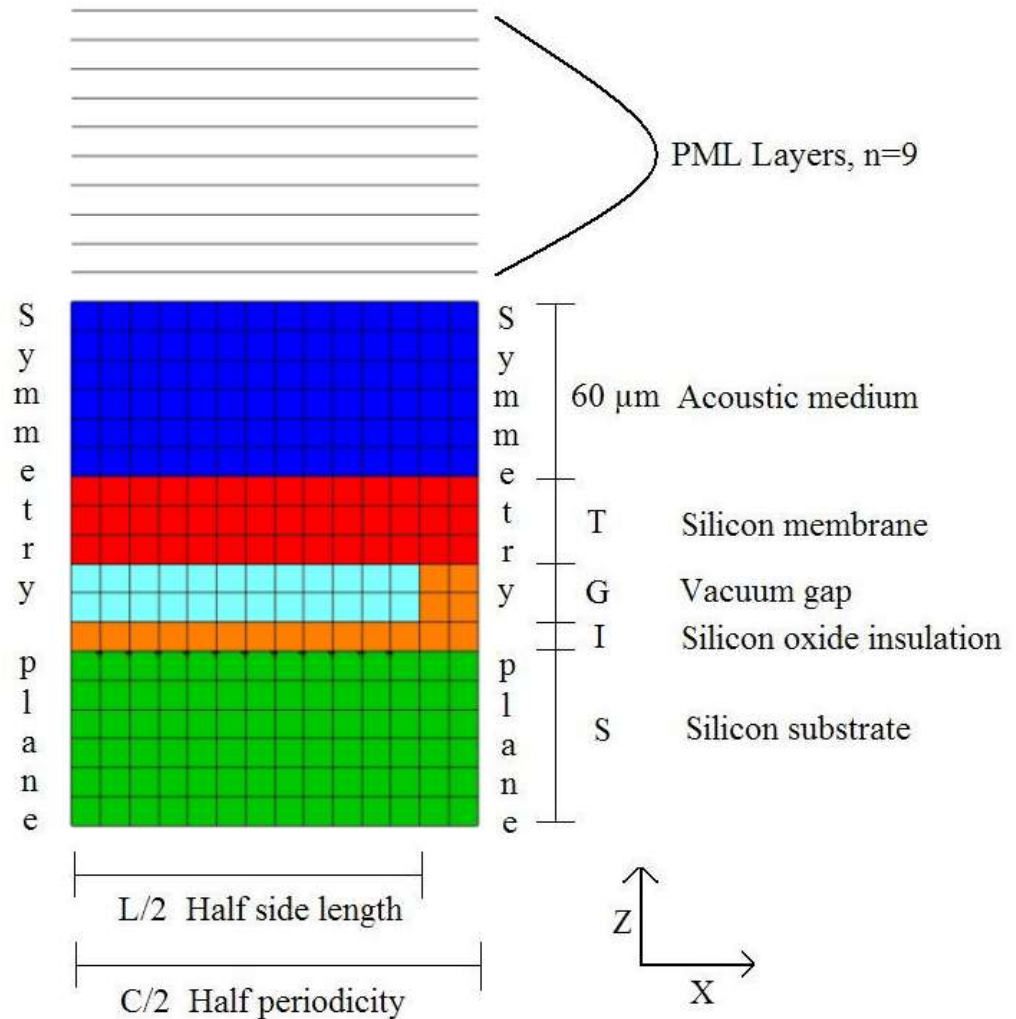
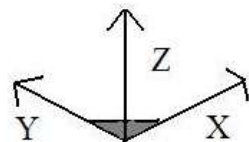
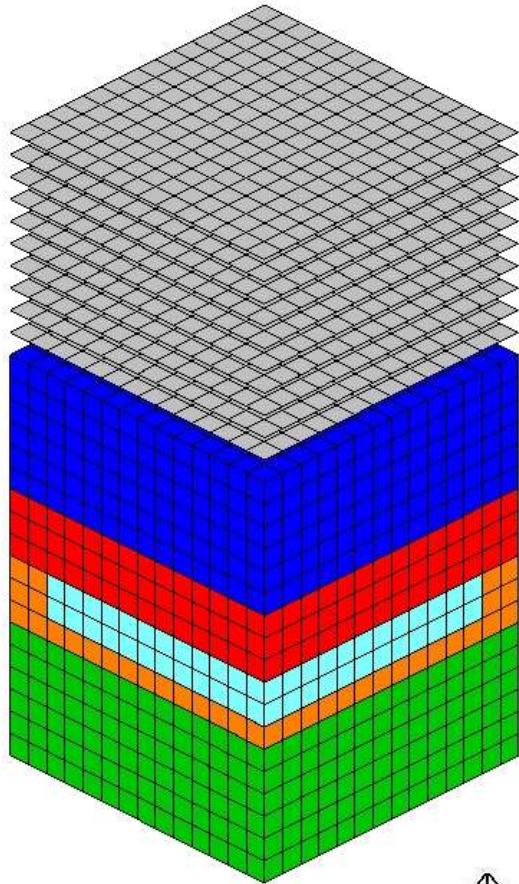
¼ of a square cMUT cell.



Infinite cMUT



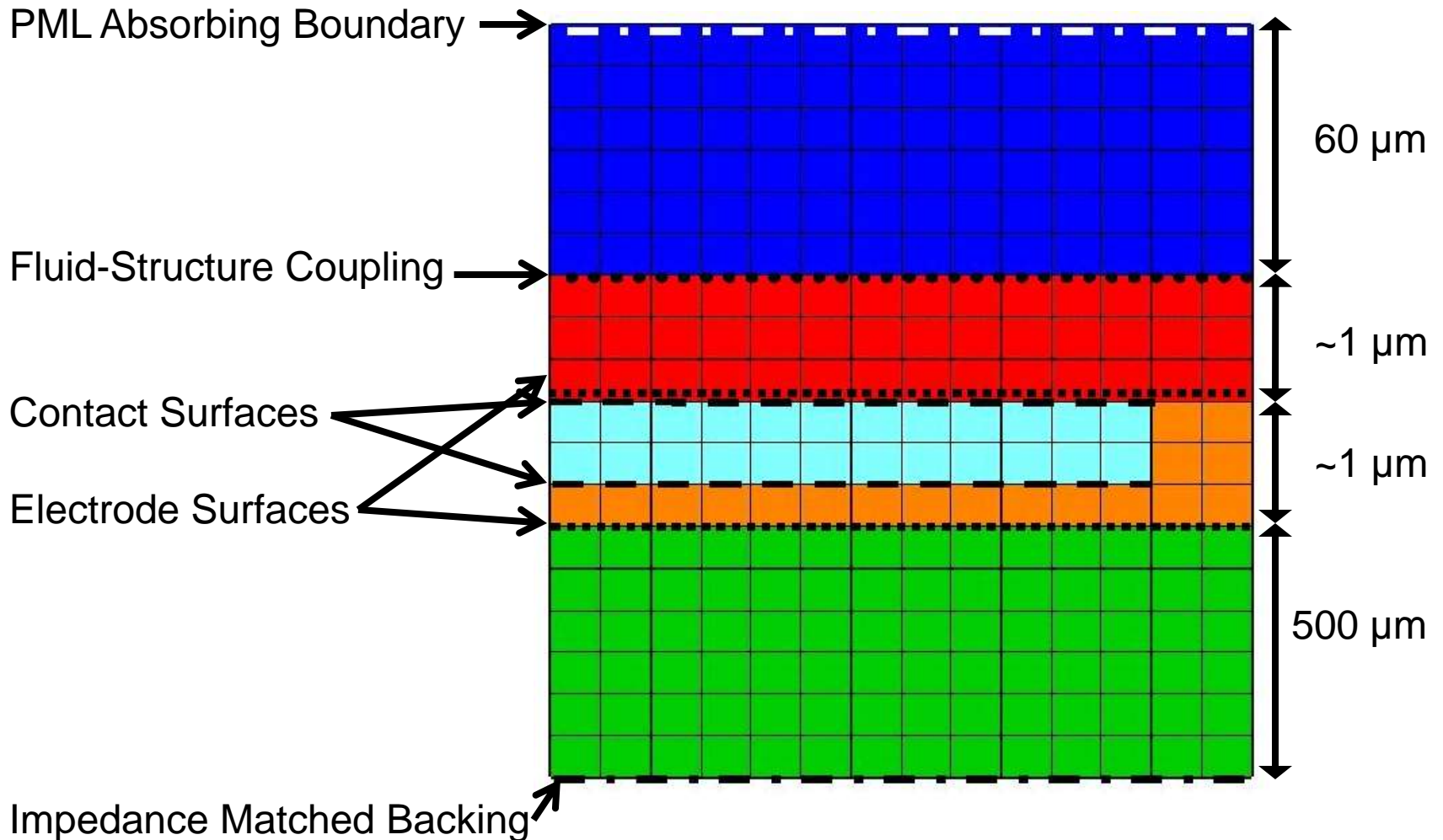
# FEM model of an infinite CMUT







# FEM model of an infinite CMUT





# Dynamic FEM Analysis

- Commercially available software (***LS-DYNA 970***)
  - Explicit, time-domain solver
- LS-DYNA built-in features
  - Fluid-structure coupling
  - Contact capability
- LS-DYNA user-defined features
  - Electrostatic-structural coupling
  - Berenger's Perfectly Matched Layer (PML) absorbing boundary
- Large Signal Characterization
  - Biasing + Pulse excitation
  - Acoustic Output Pressure

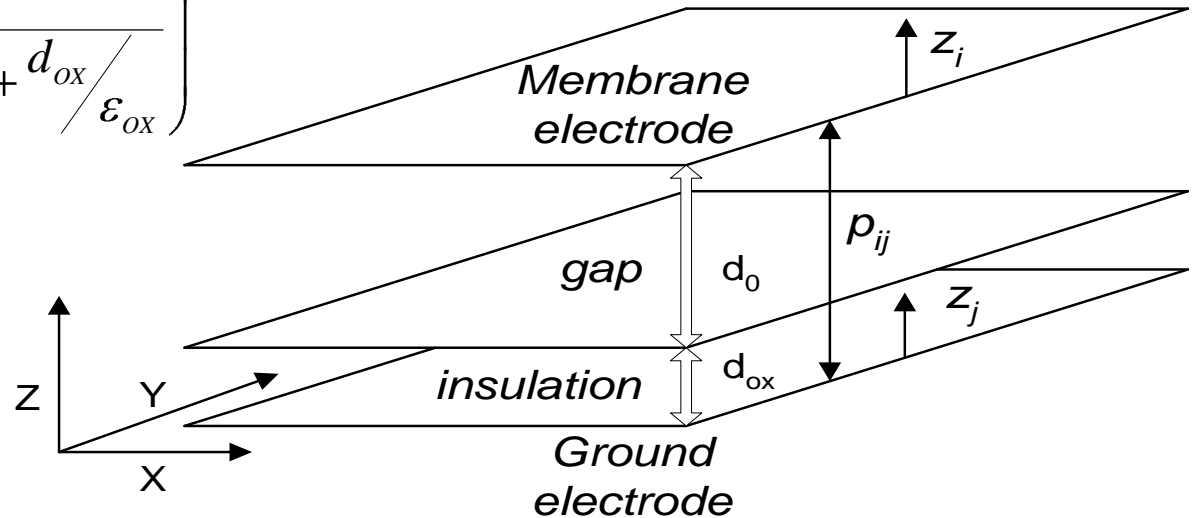




# LS-DYNA User-defined Features

## – Electrostatic-structural coupling

$$p_{ij} = \frac{1}{2} \epsilon_0 \left( \frac{V}{d_0 + (z_i - z_j) + d_{ox} / \epsilon_{ox}} \right)^2$$



Operation Regime	Bias voltage (Volt)	Average Deflection (Å) using		Percentage Difference
		ANSYS	LS-DYNA	
Conventional	83	-148	-145	2.1 %
Collapsed	83	-649	-632	2.6 %
Collapsed	101	-755	-752	0.4 %



# LS-DYNA User-defined Features

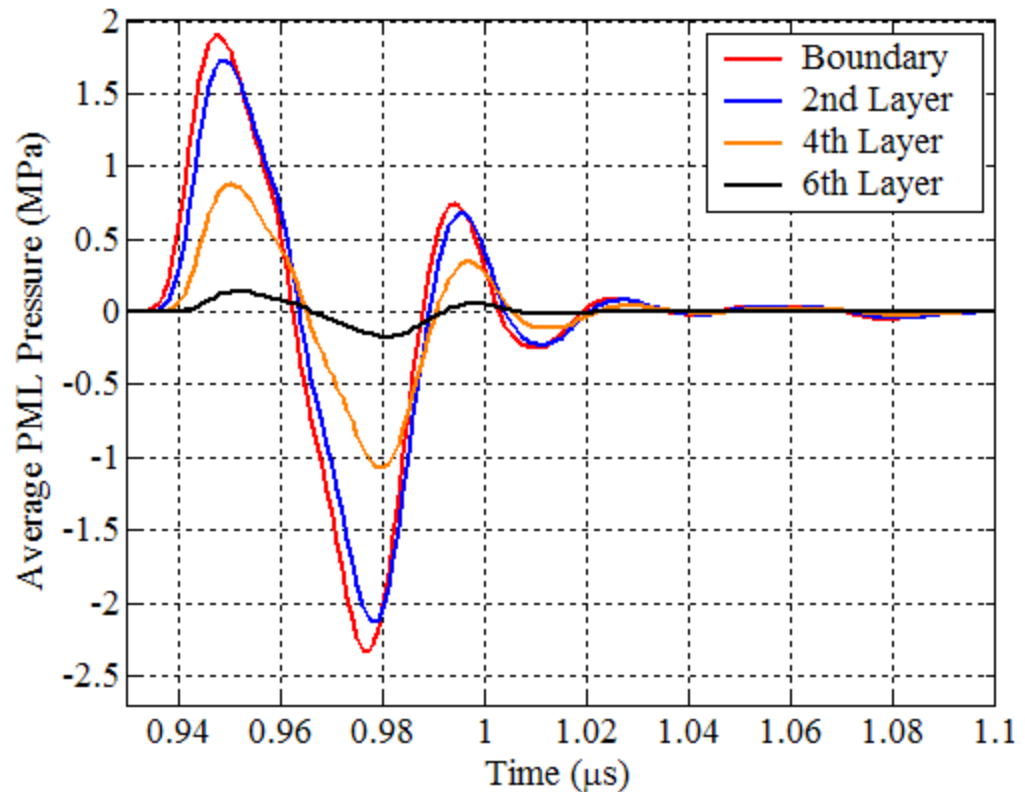
## – Berenger's Perfectly Matched Layer (PML)

Attenuation profile:

$$\alpha_{zi} = \alpha_{z_{\max}} \times \left( \frac{n-i}{n} \right)^2; n=9$$

Reflection (dB):  
-40 dB

Stability (# of  $t_{STEP}$ ):  
300,000

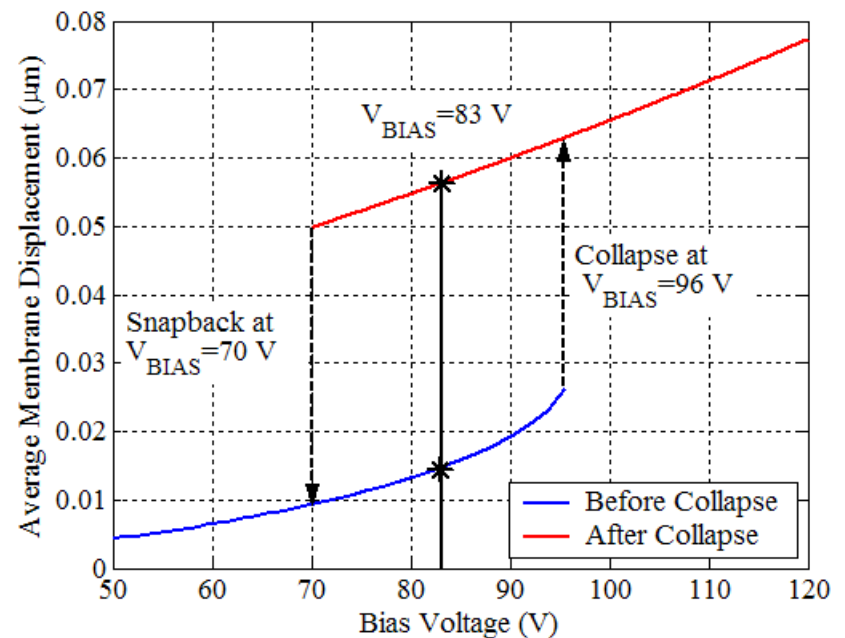




# Static FEM Results

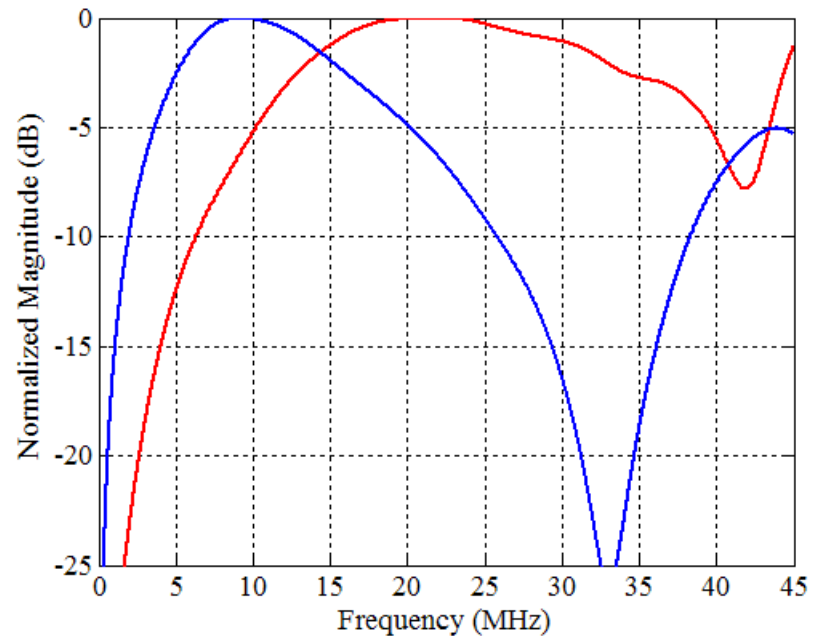
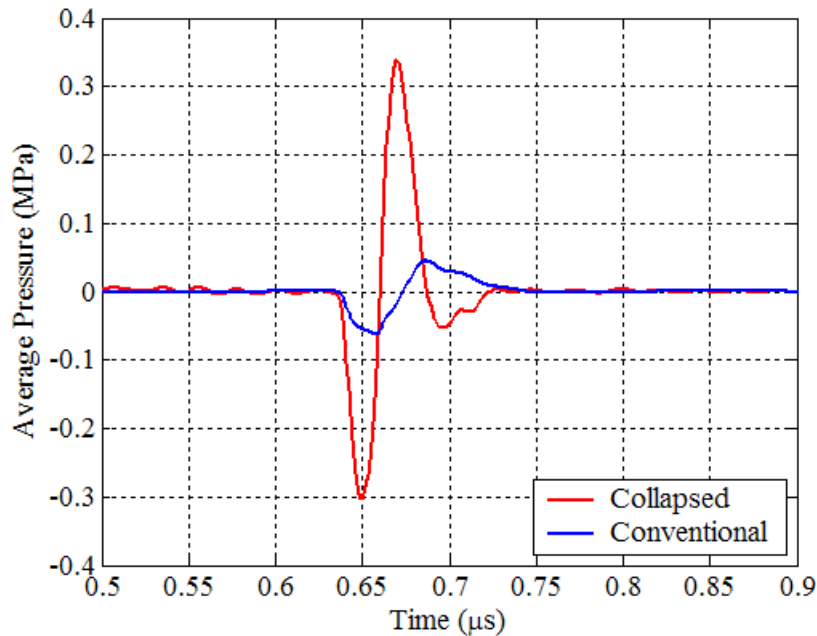
## ■ CMUT Dimensions

Side length (L) ( $\mu\text{m}$ )	<b>30</b>
Membrane thickness (T) ( $\mu\text{m}$ )	<b>1.2</b>
Gap thickness (G) ( $\mu\text{m}$ )	<b>0.18</b>
Insulating layer thickness (I) ( $\mu\text{m}$ )	<b>0.10</b>
Cell periodicity (C) ( $\mu\text{m}$ )	<b>35</b>
Substrate (S) ( $\mu\text{m}$ )	<b>500</b>





# Dynamic FEM Results



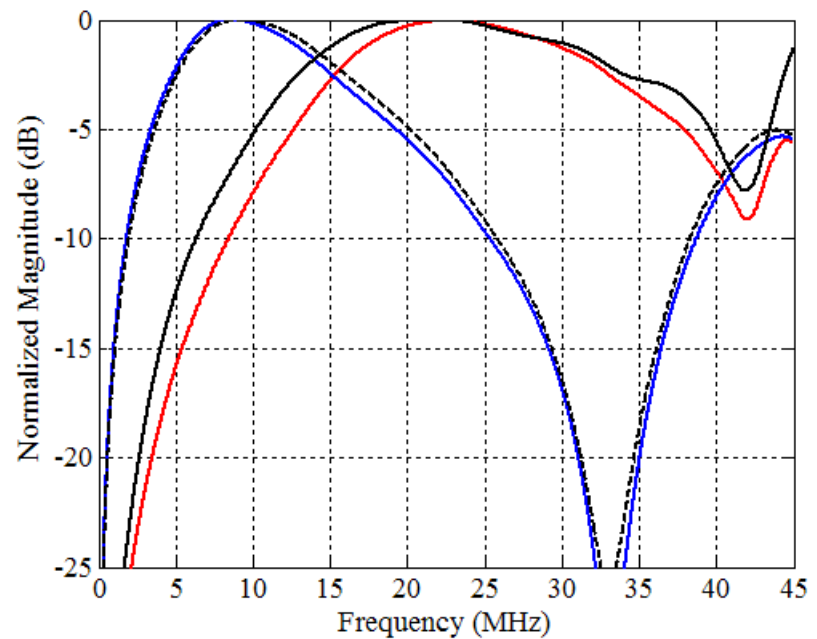
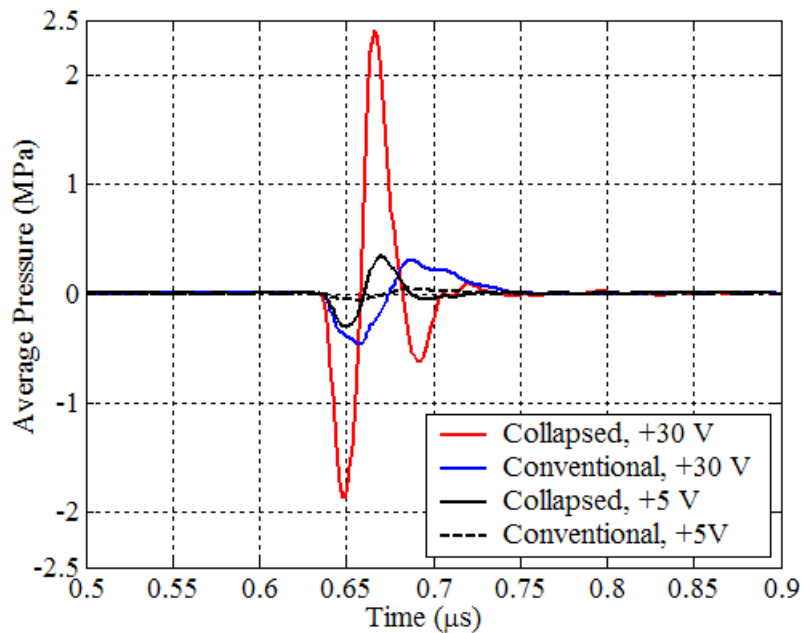
$V_{BIAS}$ (V)	$V_{PULSE}$ (V)	$t_{PULSE}$ (ns)
83	+5	20

Collapse Voltage (V)	96
Snapback Voltage (V)	70

	Conventional	Collapsed
Pressure (p-p)	107 kPa (21 kPa/V)	641 kPa (128 kPa/V)
$f_{CENTER}$ , BW (%)	9.2 MHz, 130 %	21.6 MHz, 108 %



# Dynamic FEM Results



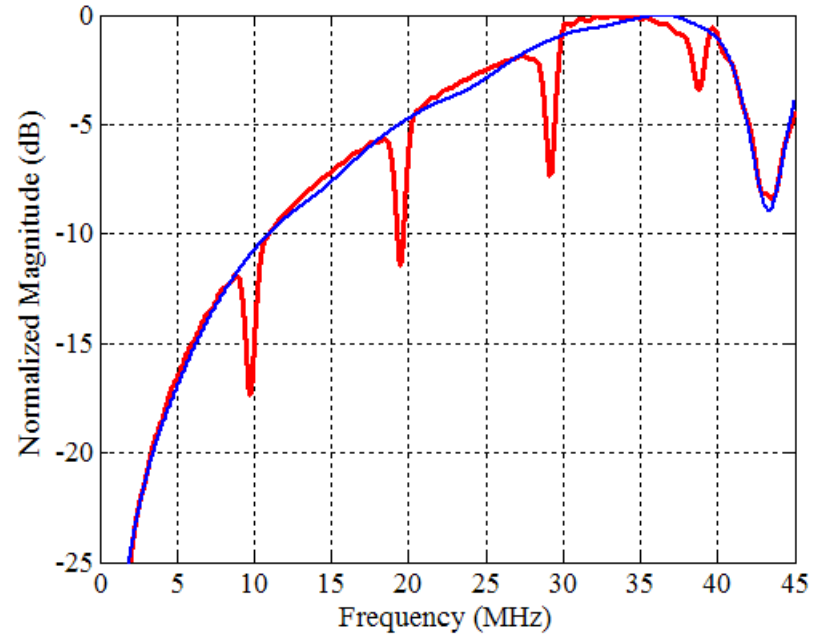
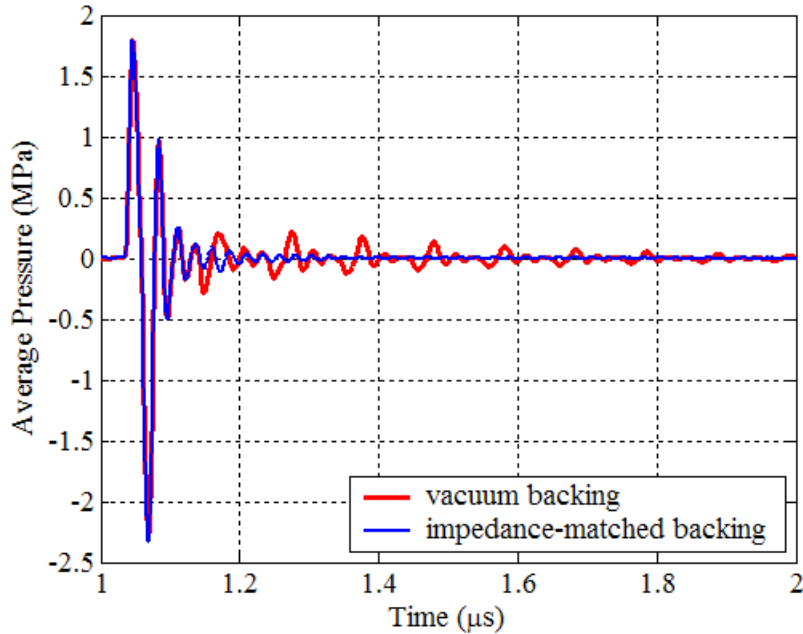
$V_{BIAS}(V)$	$V_{PULSE}(V)$	$t_{PULSE}(ns)$
83	+30	20

Collapse Voltage (V)	96
Snapback Voltage (V)	70

	Conventional	Collapsed
Pressure (p-p)	770 kPa (25 kPa/V)	4260 kPa (142 kPa/V)
$f_{CENTER}$ , BW (%)	8.6 MHz, 132 %	22.7 MHz, 84 %



# Dynamic FEM Results



$V_{BIAS}$ (V)	$V_{PULSE}$ (V)	$t_{PULSE}$ (ns)
120	-30	20

Collapse Voltage (V)	96
Snapback Voltage (V)	70

- Vacuum backing causes reflections from the bottom of the substrate.

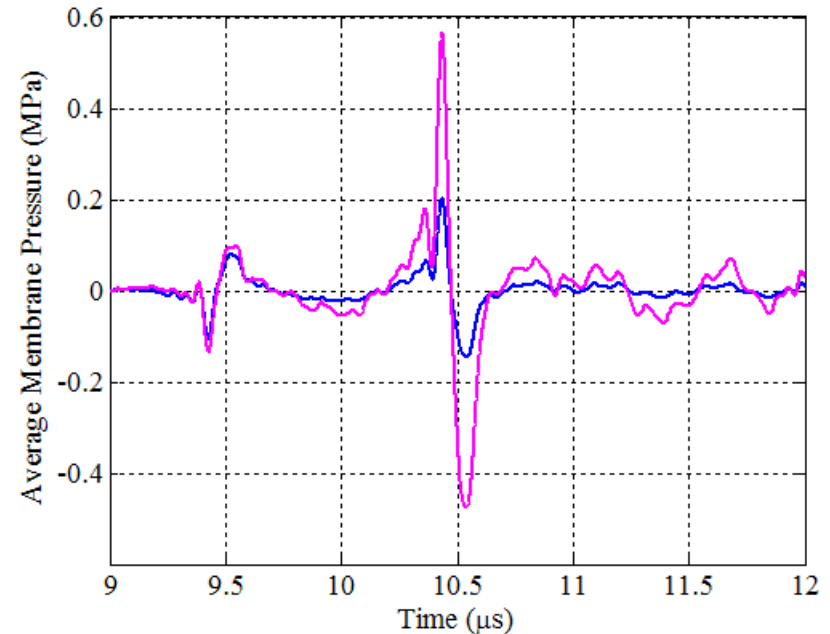


# Conventional vs. Collapse-snapback

## ■ CMUT Parameters

Length of the transducer, $\mu m$	1180
Width of the transducer, $\mu m$	280
Number of cells per element	4 x 52
Cell Shape Factor	Hexagon
Cell radius ( $r_{cell}$ ), $\mu m$	16
Electrode radius ( $r_{el}$ ), $\mu m$	8
Electrode thickness ( $t_{el}$ ), $\mu m$	0.3
Membrane thickness ( $t_m$ ), $\mu m$	1.06
Gap thickness ( $t_g$ ), $\mu m$	0.22
Insulating layer thickness ( $t_i$ ), $\mu m$	0.3
Silicon substrate thickness, $\mu m$	500
Collapse voltage, $V$	130
Snapback voltage, $V$	110

## ■ Experimental Results

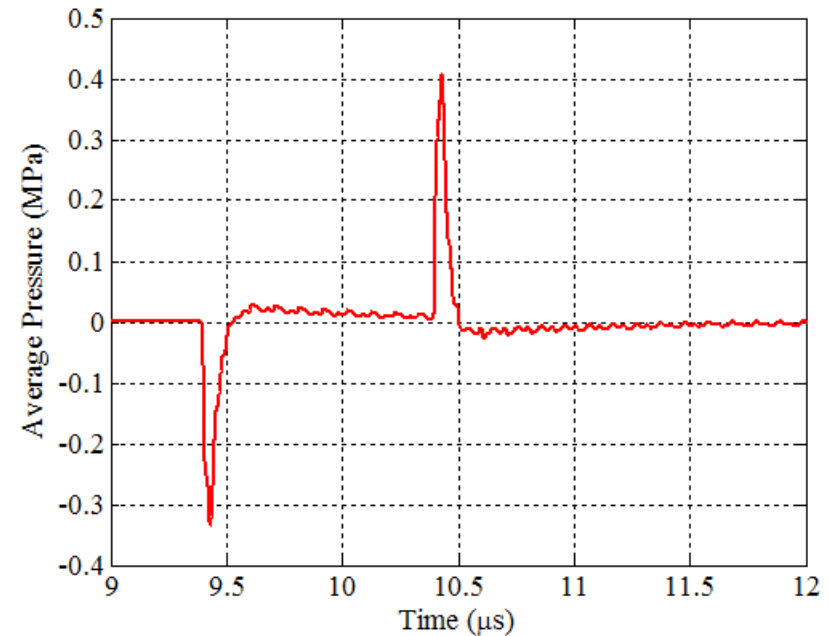
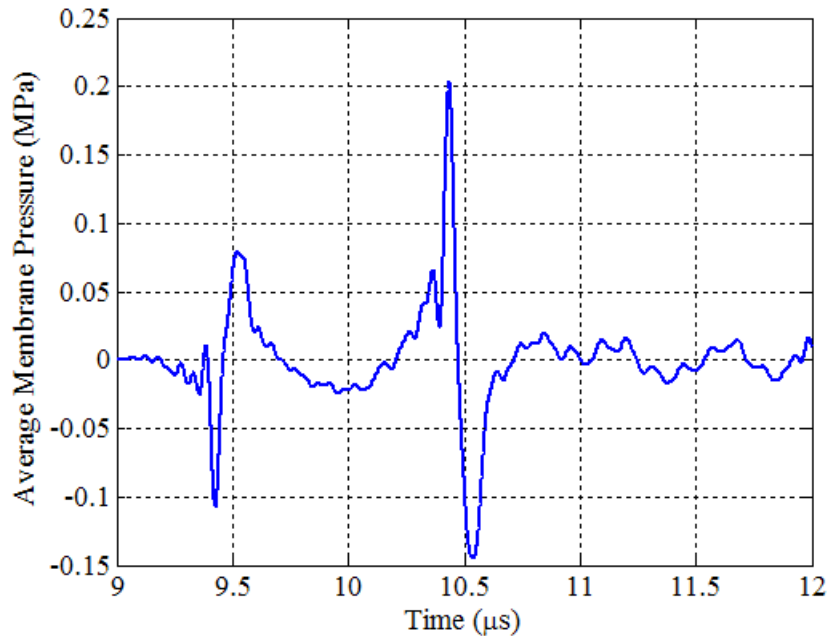


$V_{BIAS}(V)$	$V_{PULSE}(V)$	$t_{PULSE}(\mu s)$
50	+70	1
50	+90	1





# Experimental and FEM Results



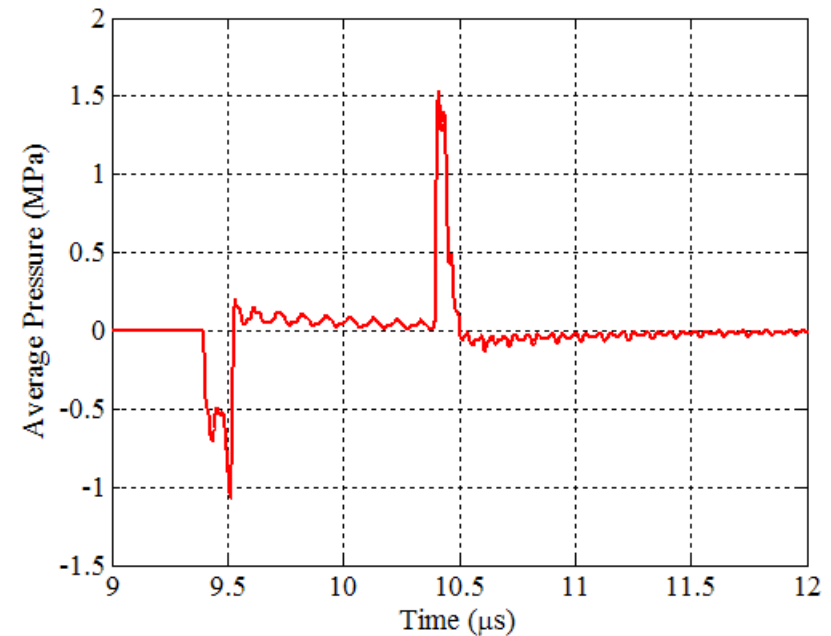
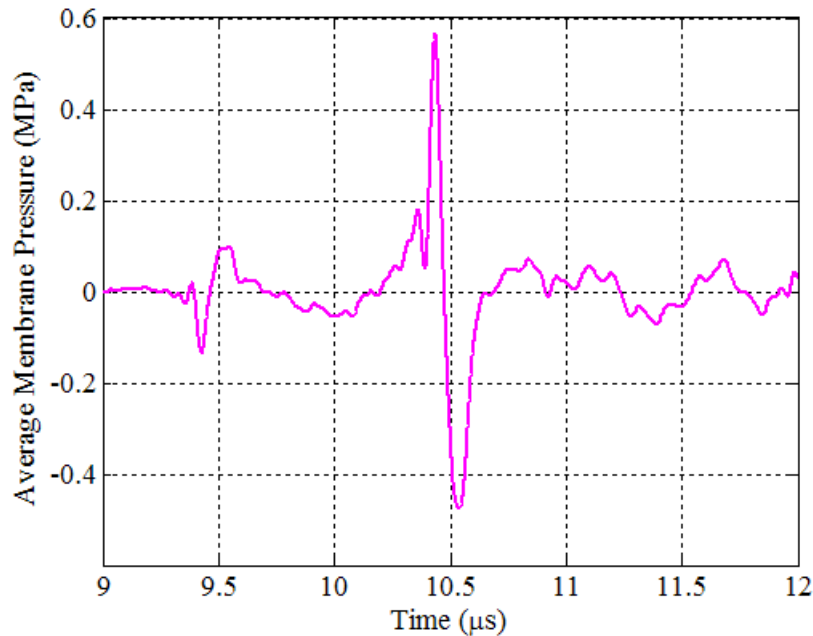
$V_{BIAS}(V)$	$V_{PULSE}(V)$	$t_{PULSE}(\mu s)$
50	+70	1

Collapse Voltage (V)	130
Snapback Voltage (V)	110

Conventional	Experimental	FEM
Pressure (p-p)	Rising, Falling 185 kPa, 348 kPa	Rising, Falling 366 kPa, 422 kPa



# Experimental and FEM Results



$V_{BIAS}$ (V)	$V_{PULSE}$ (V)	$t_{PULSE}$ ( $\mu$ s)
50	+90	1

Collapse Voltage (V)	130
Snapback Voltage (V)	110

Collapse-Snapback	Experimental	FEM
Pressure (p-p)	Collapse, Snapback 234 kPa, 1040 kPa	<b>Collapse, Snapback</b> <b>1270 kPa, 1580 kPa</b>





# More Results

- **U3-D-4** High-Frequency CMUT Arrays for High-Resolution Medical Imaging: Preliminary Results.
- **U3-D-5** CMUT Ring Arrays for Forward-looking Intravascular Imaging: Preliminary Results.



# Conclusion

- The cMUT dynamics modeled with time-domain, nonlinear, finite element method (FEM) using LS-DYNA explicit solver.
- Tested in linear (**conventional**) and nonlinear (**collapsed** and **collapse-snapback**) operation regimes.
- Good agreement between experimental and FEM results observed.
- High acoustic output pressure produced in nonlinear regimes.